

**Search Notes**

Application/Control No.

10/693,288

Examiner

Eric B. Chen

Applicant(s)/Patent under  
Reexamination

LEE, HEON

Art Unit

1765

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor search (PALM) (UPDATED)	11/22/2005	EC
EAST (all databates) (UPDATED) - see search history printout	11/22/2005	EC
216/18,22,38,39,46,47;438/3,257,710, 723,724,725,692,696; 438/745,756, 757; 216/104,107,109 (text search only)	11/22/2005	EC